


<b>Search Notes</b> 	<b>Application/Control No.</b> 10602066	<b>Applicant(s)/Patent Under Reexamination</b> MATSUDA ET AL.
	<b>Examiner</b> Tran, Thien F	<b>Art Unit</b> 2811

SEARCHED			
Class	Subclass	Date	Examiner
257	192, 336, 344, 368, 369, 403, 408	12/15/06	TT

SEARCH NOTES		
Search Notes	Date	Examiner
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INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner